



DFW

Docket No.: 060188-0456

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
YAMAGUCHI, TAKUMI, et al. : Confirmation Number: 1896
Application No.: 10/086,871 : Group Art Unit: 2811
Filed: March 04, 2002 : Examiner: Not yet assigned
For: SOLID STATE IMAGE SENSOR

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Each non-English language reference was first cited in a corresponding foreign application search report or office action and its relevance discussed therein. A copy of the

foreign search report or office action, together with an English language version thereof, is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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SHEET 1 OF 1

**INFORMATION DISCLOSURE
CITATION IN AN
APPLICATION**

(PTO-1449)

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

| EXAMINER'S INITIALS | CITE NO. | Foreign Patent Document Country Code - Number + Kind Codes (if known) | Publication Date MM-DD-YYYY | Name of Patentee or Applicant of Cited Document | Pages, Columns, Lines Where Relevant Figures Appear | Translation | |
|---------------------|----------|---|-----------------------------|---|---|----------------------------|----|
| | | | | | | Yes | No |
| | | JP 10-093066 | 04/10/1998 | TOSHIBA CORP. | | JAPAN (w/English Abstract) | |
| | | JP 2001-016502 A | 01/19/2001 | TOSHIBA CORP. | | JAPAN (w/English Abstract) | |
| | | JP 11-274455 | 10/08/1999 | TOSHIBA CORP. | | JAPAN (w/English Abstract) | |
| | | JP 2001-168310 A | 06/22/2001 | INNOTECH CORP. | | JAPAN (w/English Abstract) | |
| | | JP 2002-83949 A | 03/22/2002 | NEC CORP | | JAPAN (w/English Abstract) | |
| | | | | | | | |

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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|------------------------|-------------|---|
| EXAMINER'S INITIALS | CITE NO. | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. |
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***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.